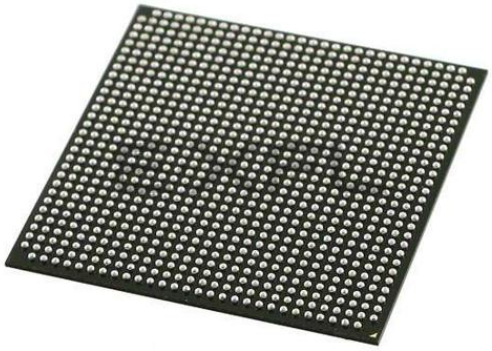

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	8962
Number of Logic Elements/Cells	190000
Total RAM Bits	13284352
Number of I/O	384
Number of Gates	-
Voltage - Supply	1.07V ~ 1.13V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	896-BBGA, FCBGA
Supplier Device Package	896-FBGA (31x31)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5agxba5d4f31i5n

Symbol	Description	Minimum	Maximum	Unit
V_{CCPLL_HPS}	HPS PLL analog power supply	–0.50	3.25	V
$V_{CC\_AUX\_SHARED}$	HPS auxiliary power supply	–0.50	3.25	V
I_{OUT}	DC output current per pin	–25	40	mA
T_J	Operating junction temperature	–55	125	°C
T_{STG}	Storage temperature (no bias)	–65	150	°C

Maximum Allowed Overshoot and Undershoot Voltage

During transitions, input signals may overshoot to the voltage listed in the following table and undershoot to –2.0 V for input currents less than 100 mA and periods shorter than 20 ns.

The maximum allowed overshoot duration is specified as a percentage of high time over the lifetime of the device. A DC signal is equivalent to 100% duty cycle.

For example, a signal that overshoots to 4.00 V can only be at 4.00 V for ~15% over the lifetime of the device; for a device lifetime of 10 years, this amounts to 1.5 years.

Table 1-2: Maximum Allowed Overshoot During Transitions for Arria V Devices

This table lists the maximum allowed input overshoot voltage and the duration of the overshoot voltage as a percentage of device lifetime.

Transceiver Power Supply Operating Conditions

Table 1-4: Transceiver Power Supply Operating Conditions for Arria V Devices

Symbol	Description	Minimum[5]	Typical	Maximum[5]	Unit
V_{CCA_GXBL}	Transceiver high voltage power (left side)	2.375	2.500	2.625	V
V_{CCA_GXBR}	Transceiver high voltage power (right side)				
V_{CCR_GXBL}	GX and SX speed grades—receiver power (left side)	1.08/1.12	1.1/1.15[6]	1.14/1.18	V
V_{CCR_GXBR}	GX and SX speed grades—receiver power (right side)				
V_{CCR_GXBL}	GT and ST speed grades—receiver power (left side)	1.17	1.20	1.23	V
V_{CCR_GXBR}	GT and ST speed grades—receiver power (right side)				
V_{CCT_GXBL}	GX and SX speed grades—transmitter power (left side)	1.08/1.12	1.1/1.15[6]	1.14/1.18	V
V_{CCT_GXBR}	GX and SX speed grades—transmitter power (right side)				
V_{CCT_GXBL}	GT and ST speed grades—transmitter power (left side)	1.17	1.20	1.23	V
V_{CCT_GXBR}	GT and ST speed grades—transmitter power (right side)				
V_{CCH_GXBL}	Transmitter output buffer power (left side)	1.425	1.500	1.575	V
V_{CCH_GXBR}	Transmitter output buffer power (right side)				

(5) The power supply value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

(6) For data rate <=3.2 Gbps, connect $V_{CCR\_GXBL/R}$, $V_{CCT\_GXBL/R}$, or $V_{CCL\_GXBL/R}$ to either 1.1-V or 1.15-V power supply. For data rate >3.2 Gbps, connect $V_{CCR\_GXBL/R}$, $V_{CCT\_GXBL/R}$, or $V_{CCL\_GXBL/R}$ to a 1.15-V power supply. For details, refer to the Arria V GT, GX, ST, and SX Device Family Pin Connection Guidelines.

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	V_{OL} (V)	V_{OH} (V)	I_{OL}[14] (mA)	I_{OH}[14] (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
HSTL-15 Class II	—	V_{REF} – 0.1	V_{REF} + 0.1	—	V_{REF} – 0.2	V_{REF} + 0.2	0.4	V_{CCIO} – 0.4	16	–16
HSTL-12 Class I	–0.15	V_{REF} – 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	V_{REF} – 0.15	V_{REF} + 0.15	0.25 × V_{CCIO}	0.75 × V_{CCIO}	8	–8
HSTL-12 Class II	–0.15	V_{REF} – 0.08	V_{REF} + 0.08	V_{CCIO}+ 0.15	V_{REF} – 0.15	V_{REF} + 0.15	0.25 × V_{CCIO}	0.75 × V_{CCIO}	16	–16
HSUL-12	—	V_{REF} – 0.13	V_{REF} + 0.13	—	V_{REF} – 0.22	V_{REF} + 0.22	0.1 × V_{CCIO}	0.9 × V_{CCIO}	—	—

Differential SSTL I/O Standards

Table 1-17: Differential SSTL I/O Standards for Arria V Devices

I/O Standard	V_{CCIO} (V)			$V_{SWING(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{SWING(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.3	V_{CCIO} + 0.6	$V_{CCIO}/2$ – 0.2	—	$V_{CCIO}/2$ + 0.2	0.62	V_{CCIO} + 0.6
SSTL-18 Class I, II	1.71	1.8	1.89	0.25	V_{CCIO} + 0.6	$V_{CCIO}/2$ – 0.175	—	$V_{CCIO}/2$ + 0.175	0.5	V_{CCIO} + 0.6
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	[15]	$V_{CCIO}/2$ – 0.15	—	$V_{CCIO}/2$ + 0.15	$2(V_{IH(AC)} - V_{REF})$	$2(V_{IL(AC)} - V_{REF})$
SSTL-135	1.283	1.35	1.45	0.18	[15]	$V_{CCIO}/2$ – 0.15	$V_{CCIO}/2$	$V_{CCIO}/2$ + 0.15	$2(V_{IH(AC)} - V_{REF})$	$2(V_{IL(AC)} - V_{REF})$

(14) To meet the I_{OL} and I_{OH} specifications, you must set the current strength settings accordingly. For example, to meet the SSTL15CI specification (8 mA), you should set the current strength settings to 8 mA. Setting at lower current strength may not meet the I_{OL} and I_{OH} specifications in the datasheet.

(15) The maximum value for $V_{SWING(DC)}$ is not defined. However, each single-ended signal needs to be within the respective single-ended limits ($V_{IH(DC)}$ and $V_{IL(DC)}$).

I/O Standard	V_{CCIO} (V)			V_{ID} (mV)[16]			$V_{ICM(DC)}$ (V)			V_{OD} (V)[17]			V_{OCM} (V)[17][18]		
	Min	Typ	Max	Min	Condition	Max	Min	Condition	Max	Min	Typ	Max	Min	Typ	Max
PCML	Transmitter, receiver, and input reference clock pins of high-speed transceivers use the PCML I/O standard. For transmitter, receiver, and reference clock I/O pin specifications, refer to Transceiver Specifications for Arria V GX and SX Devices and Transceiver Specifications for Arria V GT and ST Devices tables.														
2.5 V LVDS[19]	2.375	2.5	2.625	100	V_{CM} = 1.25 V	—	0.05	$D_{MAX} \leq$ 1.25 Gbps	1.80	0.247	—	0.6	1.125	1.25	1.375
						—	1.05	$D_{MAX} >$ 1.25 Gbps	1.55						
RSDS (HIO)[20]	2.375	2.5	2.625	100	V_{CM} = 1.25 V	—	0.25	—	1.45	0.1	0.2	0.6	0.5	1.2	1.4
Mini-LVDS (HIO)[21]	2.375	2.5	2.625	200	—	600	0.300	—	1.425	0.25	—	0.6	1	1.2	1.4
LVPECL[22]	—	—	—	300	—	—	0.60	$D_{MAX} \leq$ 700 Mbps	1.80	—	—	—	—	—	—
							1.00	$D_{MAX} >$ 700 Mbps	1.60						

Related Information

- **Transceiver Specifications for Arria V GX and SX Devices** on page 1-23
  Provides the specifications for transmitter, receiver, and reference clock I/O pin.

(16) The minimum V_{ID} value is applicable over the entire common mode range, V_{CM}.
(17) R_L range: $90 \leq R_L \leq 110\ \Omega$.
(18) This applies to default pre-emphasis setting only.
(19) For optimized LVDS receiver performance, the receiver voltage input range must be within 1.0 V to 1.6 V for data rates above 1.25 Gbps and 0 V to 1.85 V for data rates below 1.25 Gbps.
(20) For optimized RSDS receiver performance, the receiver voltage input range must be within 0.25 V to 1.45 V.
(21) For optimized Mini-LVDS receiver performance, the receiver voltage input range must be within 0.3 V to 1.425 V.
(22) For optimized LVPECL receiver performance, the receiver voltage input range must be within 0.85 V to 1.75 V for data rates above 700 Mbps and 0.45 V to 1.95 V for data rates below 700 Mbps.

Symbol/Description	Condition	Transceiver Speed Grade 4			Transceiver Speed Grade 6			Unit
		Min	Typ	Max	Min	Typ	Max	
Minimum differential eye opening at the receiver serial input pins[30]	—	100	—	—	100	—	—	mV
V_{ICM} (AC coupled)	—	—	0.7/0.75/ 0.8[31]	—	—	0.7/0.75/ 0.8 [31]	—	mV
V_{ICM} (DC coupled)	≤ 3.2Gbps[32]	670	700	730	670	700	730	mV
Differential on-chip termination resistors	85-Ω setting	—	85	—	—	85	—	Ω
	100-Ω setting	—	100	—	—	100	—	Ω
	120-Ω setting	—	120	—	—	120	—	Ω
	150-Ω setting	—	150	—	—	150	—	Ω
t_{LTR}[33]	—	—	—	10	—	—	10	µs
t_{LTD}[34]	—	4	—	—	4	—	—	µs
t_{LTD_manual}[35]	—	4	—	—	4	—	—	µs
$t_{LTR\_LTD\_manual}$[36]	—	15	—	—	15	—	—	µs
Programmable ppm detector[37]	—	±62.5, 100, 125, 200, 250, 300, 500, and 1000						ppm

(30) The differential eye opening specification at the receiver input pins assumes that you have disabled the **Receiver Equalization** feature. If you enable the **Receiver Equalization** feature, the receiver circuitry can tolerate a lower minimum eye opening, depending on the equalization level.

(31) The AC coupled V_{ICM} = 700 mV for Arria V GX and SX in PCIe mode only. The AC coupled V_{ICM} = 750 mV for Arria V GT and ST in PCIe mode only.

(32) For standard protocol compliance, use AC coupling.

(33) t_{LTR} is the time required for the receive CDR to lock to the input reference clock frequency after coming out of reset.

(34) t_{LTD} is time required for the receiver CDR to start recovering valid data after the `rx_is_lockedtodata` signal goes high.

(35) t_{LTD_manual} is the time required for the receiver CDR to start recovering valid data after the `rx_is_lockedtodata` signal goes high when the CDR is functioning in the manual mode.

(36) $t_{LTR\_LTD\_manual}$ is the time the receiver CDR must be kept in lock to reference (LTR) mode after the `rx_is_lockedtoref` signal goes high when the CDR is functioning in the manual mode.

Symbol	Parameter	Condition	Min	Typ	Max	Unit
t_{OUTPJ_DC}[67]	Period jitter for dedicated clock output in integer PLL	$F_{OUT} \geq 100$ MHz	—	—	175	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	17.5	mUI (p-p)
t_{FOUTPJ_DC}[67]	Period jitter for dedicated clock output in fractional PLL	$F_{OUT} \geq 100$ MHz	—	—	250[68], 175[69]	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	25[68], 17.5[69]	mUI (p-p)
t_{OUTCCJ_DC}[67]	Cycle-to-cycle jitter for dedicated clock output in integer PLL	$F_{OUT} \geq 100$ MHz	—	—	175	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	17.5	mUI (p-p)
$t_{FOUTCCJ\_DC}$[67]	Cycle-to-cycle jitter for dedicated clock output in fractional PLL	$F_{OUT} \geq 100$ MHz	—	—	250[68], 175[69]	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	25[68], 17.5[69]	mUI (p-p)
t_{OUTPJ_IO}[67][70]	Period jitter for clock output on a regular I/O in integer PLL	$F_{OUT} \geq 100$ MHz	—	—	600	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	60	mUI (p-p)
t_{FOUTPJ_IO}[67][68][70]	Period jitter for clock output on a regular I/O in fractional PLL	$F_{OUT} \geq 100$ MHz	—	—	600	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	60	mUI (p-p)
t_{OUTCCJ_IO}[67][70]	Cycle-to-cycle jitter for clock output on a regular I/O in integer PLL	$F_{OUT} \geq 100$ MHz	—	—	600	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	60	mUI (p-p)
$t_{FOUTCCJ\_IO}$[67][68][70]	Cycle-to-cycle jitter for clock output on a regular I/O in fractional PLL	$F_{OUT} \geq 100$ MHz	—	—	600	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	60	mUI (p-p)

(67) Peak-to-peak jitter with a probability level of 10^{-12} (14 sigma, 99.99999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL, when an input jitter of 30 ps is applied. The external memory interface clock output jitter specifications use a different measurement method and are available in Memory Output Clock Jitter Specification for Arria V Devices table.

(68) This specification only covered fractional PLL for low bandwidth. The f_{VCO} for fractional value range 0.05–0.95 must be ≥ 1000 MHz.

(69) This specification only covered fractional PLL for low bandwidth. The f_{VCO} for fractional value range 0.20–0.80 must be ≥ 1200 MHz.

(70) External memory interface clock output jitter specifications use a different measurement method, which are available in Memory Output Clock Jitter Specification for Arria V Devices table.

Table 1-38: Memory Block Performance Specifications for Arria V Devices

Memory	Mode	Resources Used		Performance			Unit
		ALUTs	Memory	–I3, –C4	–I5, –C5	–C6	
MLAB	Single port, all supported widths	0	1	500	450	400	MHz
	Simple dual-port, all supported widths	0	1	500	450	400	MHz
	Simple dual-port with read and write at the same address	0	1	400	350	300	MHz
	ROM, all supported width	—	—	500	450	400	MHz
M10K Block	Single-port, all supported widths	0	1	400	350	285	MHz
	Simple dual-port, all supported widths	0	1	400	350	285	MHz
	Simple dual-port with the read-during-write option set to **Old Data**, all supported widths	0	1	315	275	240	MHz
	True dual port, all supported widths	0	1	400	350	285	MHz
	ROM, all supported widths	0	1	400	350	285	MHz

Internal Temperature Sensing Diode Specifications

Table 1-39: Internal Temperature Sensing Diode Specifications for Arria V Devices

Temperature Range	Accuracy	Offset Calibrated Option	Sampling Rate	Conversion Time	Resolution	Minimum Resolution with no Missing Codes
–40 to 100°C	±8°C	No	1 MHz	< 100 ms	8 bits	8 bits

Periphery Performance

This section describes the periphery performance, high-speed I/O, and external memory interface.

Actual achievable frequency depends on design and system specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specifications

Figure 1-5: LVDS Soft-Clock Data Recovery (CDR)/DPA Sinusoidal Jitter Tolerance Specification for a Data Rate Equal to 1.25 Gbps

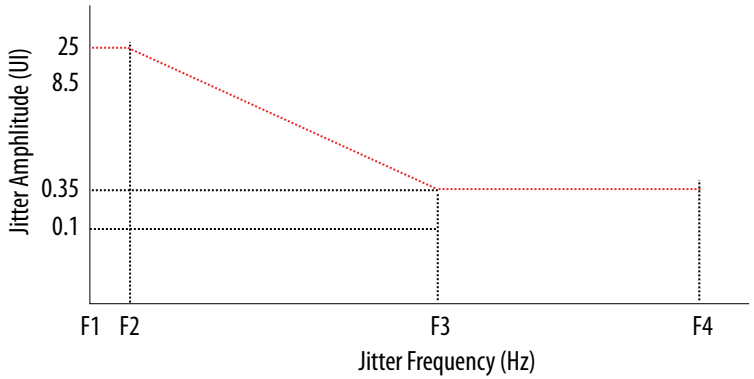
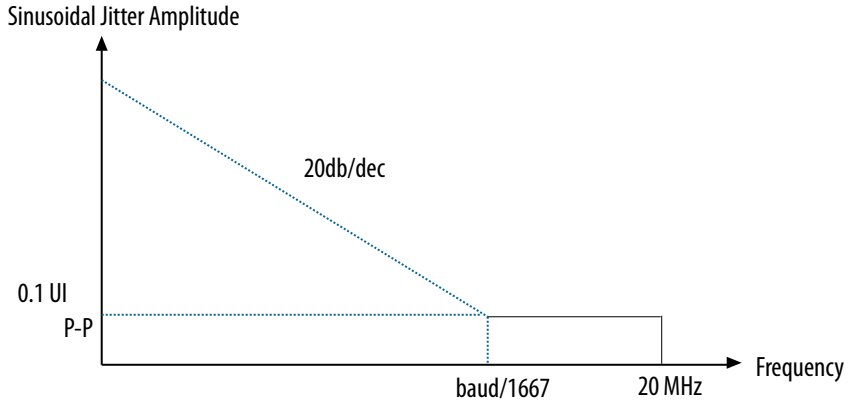


Table 1-42: LVDS Soft-CDR/DPA Sinusoidal Jitter Mask Values for a Data Rate Equal to 1.25 Gbps

Jitter Frequency (Hz)		Sinusoidal Jitter (UI)
F1	10,000	25.000
F2	17,565	25.000
F3	1,493,000	0.350
F4	50,000,000	0.350

Figure 1-6: LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for a Data Rate Less than 1.25 Gbps



DLL Frequency Range Specifications

Table 1-43: DLL Frequency Range Specifications for Arria V Devices

Parameter	–I3, –C4	–I5, –C5	–C6	Unit
DLL operating frequency range	200 – 667	200 – 667	200 – 667	MHz

DQS Logic Block Specifications

Table 1-44: DQS Phase Shift Error Specifications for DLL-Delayed Clock (t_{DQS_PSERR}) for Arria V Devices

This error specification is the absolute maximum and minimum error.

Number of DQS Delay Buffer	–I3, –C4	–I5, –C5	–C6	Unit
2	40	80	80	ps

Symbol	Description	Min	Max	Unit
T_h	SPI MISO hold time	1	—	ns
$T_{dutycycle}$	SPI_CLK duty cycle	45	55	%
$T_{dssfrst}$	Output delay SPI_SS valid before first clock edge	8	—	ns
T_{dsslst}	Output delay SPI_SS valid after last clock edge	8	—	ns
T_{dio}	Master-out slave-in (MOSI) output delay	–1	1	ns

(86) This value is based on `rx_sample_dly` = 1 and `spi_m_clk` = 120 MHz. `spi_m_clk` is the internal clock that is used by SPI Master to derive it's `SCLK_OUT`. These timings are based on `rx_sample_dly` of 1. This delay can be adjusted as needed to accommodate slower response times from the slave. Note that a delay of 0 is not allowed. The setup time can be used as a reference starting point. It is very crucial to do a calibration to get the correct `rx_sample_dly` value because each SPI slave device may have different output delay and each application board may have different path delay. For more information about `rx_sample_delay`, refer to the SPI Controller chapter in the Hard Processor System Technical Reference Manual.

After the Boot ROM code exits and control is passed to the preloader, software can adjust the value of `drvsel` and `smplsel` via the system manager. `drvsel` can be set from 1 to 7 and `smplsel` can be set from 0 to 7. While the preloader is executing, the values for `SDMMC_CLK` and `SDMMC_CLK_OUT` increase to a maximum of 200 MHz and 50 MHz respectively.

The SD/MMC interface calibration support will be available in a future release of the preloader through the SoC EDS software update.

Symbol	Description	Min	Max	Unit
T_{sdmmc_clk} (internal reference clock)	SDMMC_CLK clock period (Identification mode)	20	—	ns
	SDMMC_CLK clock period (Default speed mode)	5	—	ns
	SDMMC_CLK clock period (High speed mode)	5	—	ns
$T_{sdmmc\_clk\_out}$ (interface output clock)	SDMMC_CLK_OUT clock period (Identification mode)	2500	—	ns
	SDMMC_CLK_OUT clock period (Default speed mode)	40	—	ns
	SDMMC_CLK_OUT clock period (High speed mode)	20	—	ns
$T_{dutycycle}$	SDMMC_CLK_OUT duty cycle	45	55	%
T_d	SDMMC_CMD/SDMMC_D output delay	(T_{sdmmc_clk} × `drvsel`)/2 – 1.23 (87)	(T_{sdmmc_clk} × `drvsel`)/2 + 1.69 (87)	ns
T_{su}	Input setup time	1.05 – (T_{sdmmc_clk} × `smplsel`)/2 (88)	—	ns
T_h	Input hold time	(T_{sdmmc_clk} × `smplsel`)/2 (88)	—	ns

(87) `drvsel` is the drive clock phase shift select value.
(88) `smplsel` is the sample clock phase shift select value.

Lower number refers to faster speed grade.

L = Low power devices.

Transceiver Speed Grade	Core Speed Grade			
	C3	C4	I3L	I4
2	Yes	—	Yes	—
3	—	Yes	—	Yes

Absolute Maximum Ratings

Absolute maximum ratings define the maximum operating conditions for Arria V GZ devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied for these conditions.

Caution: Conditions other than those listed in the following table may cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.

Table 2-2: Absolute Maximum Ratings for Arria V GZ Devices

Symbol	Description	Minimum	Maximum	Unit
V_{CC}	Power supply for core voltage and periphery circuitry	–0.5	1.35	V
V_{CCPT}	Power supply for programmable power technology	–0.5	1.8	V
V_{CCPGM}	Power supply for configuration pins	–0.5	3.9	V
V_{CC_AUX}	Auxiliary supply for the programmable power technology	–0.5	3.4	V
V_{CCBAT}	Battery back-up power supply for design security volatile key register	–0.5	3.9	V
V_{CCPD}	I/O pre-driver power supply	–0.5	3.9	V
V_{CCIO}	I/O power supply	–0.5	3.9	V
V_{CCD_FPLL}	PLL digital power supply	–0.5	1.8	V
V_{CCA_FPLL}	PLL analog power supply	–0.5	3.4	V

Transceiver Power Supply Requirements

Table 2-7: Transceiver Power Supply Voltage Requirements for Arria V GZ Devices

Conditions	VCCR_GXB and VCCT_GXB (122)	VCCA_GXB	VCCH_GXB	Unit
If BOTH of the following conditions are true: • Data rate > 10.3 Gbps. • DFE is used.	1.05	3.0	1.5	V
If ANY of the following conditions are true (123) : • ATX PLL is used. • Data rate > 6.5Gbps. • DFE (data rate ≤ 10.3 Gbps), AEQ, or EyeQ feature is used.	1.0			
If ALL of the following conditions are true: • ATX PLL is not used. • Data rate ≤ 6.5Gbps. • DFE, AEQ, and EyeQ are not used.	0.85	2.5		

DC Characteristics

Supply Current

Standby current is the current drawn from the respective power rails used for power budgeting.

Use the Excel-based Early Power Estimator (EPE) to get supply current estimates for your design because these currents vary greatly with the resources you use.

(122) If the VCCR_GXB and VCCT_GXB supplies are set to 1.0 V or 1.05 V, they cannot be shared with the VCC core supply. If the VCCR_GXB and VCCT_GXB are set to 0.85 V, they can be shared with the VCC core supply.

(123) Choose this power supply voltage requirement option if you plan to upgrade your design later with any of the listed conditions.

Symbol	Description	Conditions	Resistance Tolerance		Unit
			C3, I3L	C4, I4	
25-Ω R_S	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 1.8 and 1.5 V	±40	±40	%
25-Ω R_S	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 1.2 V	±50	±50	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.8 and 1.5 V	±40	±40	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.2 V	±50	±50	%
100-Ω R_D	Internal differential termination (100-Ω setting)	V_{CCIO} = 2.5 V	±25	±25	%

Figure 2-1: OCT Variation Without Re-Calibration for Arria V GZ Devices

$$R_{OCT} = R_{SCAL}\left(1 + \left(\frac{dR}{dT} \times \triangle T\right) \pm \left(\frac{dR}{dV} \times \triangle V\right)\right)$$

Notes:
1. The R_{OCT} value shows the range of OCT resistance with the variation of temperature and V_{CCIO}.
2. R_{SCAL} is the OCT resistance value at power-up.
3. ΔT is the variation of temperature with respect to the temperature at power-up.
4. ΔV is the variation of voltage with respect to the V_{CCIO} at power-up.
5. dR/dT is the percentage change of R_{SCAL} with temperature.
6. dR/dV is the percentage change of R_{SCAL} with voltage.

Table 2-12: OCT Variation after Power-Up Calibration for Arria V GZ Devices

Valid for a V_{CCIO} range of ±5% and a temperature range of 0° to 85°C.

Hot Socketing

Table 2-14: Hot Socketing Specifications for Arria V GZ Devices

Symbol	Description	Maximum
$I_{IOPIN\ (DC)}$	DC current per I/O pin	300 µA
$I_{IOPIN\ (AC)}$	AC current per I/O pin	8 mA (124)
$I_{XCVR\text{-}TX\ (DC)}$	DC current per transceiver transmitter pin	100 mA
$I_{XCVR\text{-}RX\ (DC)}$	DC current per transceiver receiver pin	50 mA

Internal Weak Pull-Up Resistor

Table 2-15: Internal Weak Pull-Up Resistor for Arria V GZ Devices

All I/O pins have an option to enable the weak pull-up resistor except the configuration, test, and JTAG pins. The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 kΩ .

Symbol	Description	V_{CCIO} Conditions (V) (125)	Value (126)	Unit
R_{PU}	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option.	3.0 ±5%	25	k Ω
		2.5 ±5%	25	k Ω
		1.8 ±5%	25	k Ω
		1.5 ±5%	25	kΩ
		1.35 ±5%	25	k Ω
		1.25 ±5%	25	k Ω
		1.2 ±5%	25	k Ω

(124) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|I_{IOPIN}| = C\ dv/dt$, in which C is the I/O pin capacitance and dv/dt is the slew rate.
(125) The pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.
(126) These specifications are valid with a ±10% tolerance to cover changes over PVT.

Switching Characteristics

Transceiver Performance Specifications

Reference Clock

Table 2-22: Reference Clock Specifications for Arria V GZ Devices

Speed grades shown refer to the PMA Speed Grade in the device ordering code. The maximum data rate could be restricted by the Core/PCS speed grade. Contact your Altera Sales Representative for the maximum data rate specifications in each speed grade combination offered. For more information about device ordering codes, refer to the *Arria V Device Overview*.

Symbol/Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Reference Clock								
Supported I/O Standards	Dedicated reference clock pin	1.2-V PCML, 1.4-V PCML, 1.5-V PCML, 2.5-V PCML, Differential LVPECL, LVDS, and HCSL						
	RX reference clock pin	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS						
Input Reference Clock Frequency (CMU PLL) (137)	—	40	—	710	40	—	710	MHz
Input Reference Clock Frequency (ATX PLL)(137)	—	100	—	710	100	—	710	MHz

(137) The input reference clock frequency options depend on the data rate and the device speed grade.

Symbol/Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Rise time	Measure at ±60 mV of differential signal (138)	—	—	400	—	—	400	ps
Fall time	Measure at ±60 mV of differential signal (138)	—	—	400	—	—	400	
Duty cycle	—	45	—	55	45	—	55	%
Spread-spectrum modulating clock frequency	PCI Express ®(PCIe)	30	—	33	30	—	33	kHz
Spread-spectrum downspread	PCIe	—	0 to –0.5	—	—	0 to –0.5	—	%
On-chip termination resistors	—	—	100	—	—	100	—	Ω
Absolute V_{MAX}	Dedicated reference clock pin	—	—	1.6	—	—	1.6	V
	RX reference clock pin	—	—	1.2	—	—	1.2	
Absolute V_{MIN}	—	–0.4	—	—	–0.4	—	—	V
Peak-to-peak differential input voltage	—	200	—	1600	200	—	1600	mV
V_{ICM} (AC coupled)	Dedicated reference clock pin	1000/900/850 (139)			1000/900/850 (139)			mV
	RX reference clock pin	1.0/0.9/0.85 (140)			1.0/0.9/0.85(140)			mV
V_{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250	—	550	250	—	550	mV

(138) REFCLK performance requires to meet transmitter REFCLK phase noise specification.
(139) The reference clock common mode voltage is equal to the V_{CCR_GXB} power supply level.
(140) This supply follows VCCR_GXB

Symbol	Parameter	Min	Typ	Max	Unit
t_{INCCJ} (171), (172)	Input clock cycle-to-cycle jitter (f_{REF} ≥ 100 MHz)	—	—	0.15	UI (p-p)
	Input clock cycle-to-cycle jitter (f_{REF} < 100 MHz)	-750	—	+750	ps (p-p)
t_{OUTPJ_DC} (173)	Period Jitter for dedicated clock output in integer PLL (f_{OUT} ≥ 100 MHz)	—	—	175	ps (p-p)
	Period Jitter for dedicated clock output in integer PLL (f_{OUT} < 100 Mhz)	—	—	17.5	mUI (p-p)
t_{FOUTPJ_DC} (173)	Period Jitter for dedicated clock output in fractional PLL (f_{OUT} ≥ 100 MHz)	—	—	250(176), 175(174)	ps (p-p)
	Period Jitter for dedicated clock output in fractional PLL (f_{OUT} < 100 MHz)	—	—	25(176), 17.5 (174)	mUI (p-p)
t_{OUTCCJ_DC} (173)	Cycle-to-cycle Jitter for a dedicated clock output in integer PLL (f_{OUT} ≥ 100 MHz)	—	—	175	ps (p-p)
	Cycle-to-cycle Jitter for a dedicated clock output in integer PLL (f_{OUT} < 100 MHz)	—	—	17.5	mUI (p-p)
$t_{FOUTCCJ\_DC}$ (173)	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL (f_{OUT} ≥ 100 MHz)	—	—	250(176), 175 (174)	ps (p-p)
	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL (f_{OUT} < 100 MHz)	—	—	25(176), 17.5 (174)	mUI (p-p)

(171) A high input jitter directly affects the PLL output jitter. To have low PLL output clock jitter, you must provide a clean clock source with jitter < 120 ps.
(172) The f_{REF} is fIN/N specification applies when N = 1.
(173) Peak-to-peak jitter with a probability level of 10^{-12} (14 sigma, 99.99999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL, when an input jitter of 30 ps is applied. The external memory interface clock output jitter specifications use a different measurement method and are available in the "Worst-Case DCD on Arria V GZ I/O Pins" table.
(174) This specification only covered fractional PLL for low bandwidth. The f_{VCO} for fractional value range 0.20–0.80 must be ≥ 1200 MHz.

OCT Calibration Block Specifications

Table 2-51: OCT Calibration Block Specifications for Arria V GZ Devices

Symbol	Description	Min	Typ	Max	Unit
OCTUSRCLK	Clock required by the OCT calibration blocks	—	—	20	MHz
T_{OCTCAL}	Number of OCTUSRCLK clock cycles required for OCT R_S/R_T calibration	—	1000	—	Cycles
$T_{OCTSHIFT}$	Number of OCTUSRCLK clock cycles required for the OCT code to shift out	—	32	—	Cycles
T_{RS_RT}	Time required between the `dyn_term_ctrl` and `oe` signal transitions in a bidirectional I/O buffer to dynamically switch between OCT R_S and R_T (See the figure below.)	—	2.5	—	ns

Figure 2-6: Timing Diagram for `oe` and `dyn_term_ctrl` Signals

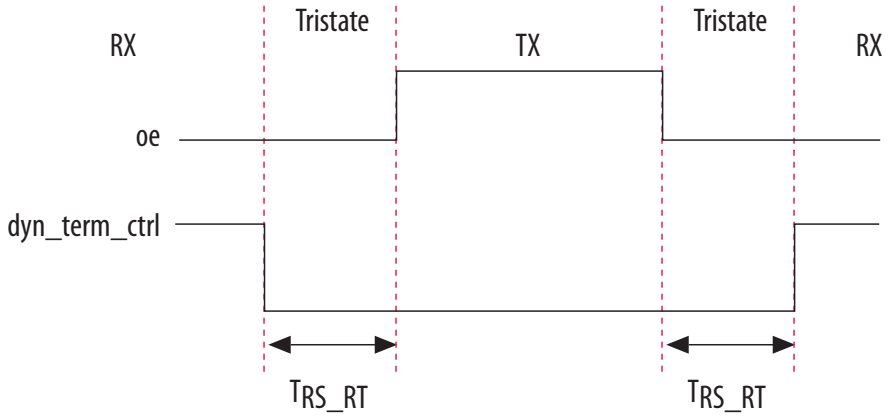


Table 2-57: FPP Timing Parameters for Arria V GZ Devices When the DCLK-to-DATA[] Ratio is >1

Use these timing parameters when you use the decompression and design security features.

Symbol	Parameter	Minimum	Maximum	Unit
t_{CF2CD}	nCONFIG low to CONF_DONE low	—	600	ns
t_{CF2ST0}	nCONFIG low to nSTATUS low	—	600	ns
t_{CFG}	nCONFIG low pulse width	2	—	µs
t_{STATUS}	nSTATUS low pulse width	268	1,506 (210)	µs
t_{CF2ST1}	nCONFIG high to nSTATUS high	—	1,506 (211)	µs
t_{CF2CK} (212)	nCONFIG high to first rising edge on DCLK	1,506	—	µs
t_{ST2CK} (212)	nSTATUS high to first rising edge of DCLK	2	—	µs
t_{DSU}	DATA[] setup time before rising edge on DCLK	5.5	—	ns
t_{DH}	DATA[] hold time after rising edge on DCLK	$N-1/f_{DCLK}$ (213)	—	s
t_{CH}	DCLK high time	$0.45 \times 1/f_{MAX}$	—	s
t_{CL}	DCLK low time	$0.45 \times 1/f_{MAX}$	—	s
t_{CLK}	DCLK period	$1/f_{MAX}$	—	s
f_{MAX}	DCLK frequency (FPP ×8/×16)	—	125	MHz
	DCLK frequency (FPP ×32)	—	100	MHz
t_R	Input rise time	—	40	ns
t_F	Input fall time	—	40	ns
t_{CD2UM}	CONF_DONE high to user mode (214)	175	437	µs

(210) You can obtain this value if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
(211) You can obtain this value if you do not delay configuration by externally holding the nSTATUS low.
(212) If nSTATUS is monitored, follow the t_{ST2CK} specification. If nSTATUS is not monitored, follow the t_{CF2CK} specification.
(213) N is the DCLK-to-DATA ratio and f_{DCLK} is the DCLK frequency the system is operating.
(214) The minimum and maximum numbers apply only if you use the internal oscillator as the clock source for initializing the device.